


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565106	<b>Applicant(s)/Patent Under Reexamination</b> HAN ET AL.
	<b>Examiner</b> M. Lee	<b>Art Unit</b> 2622

SEARCHED			
Class	Subclass	Date	Examiner
348	515, 518, 484, 194	5/5/09	ml

SEARCH NOTES		
Search Notes	Date	Examiner
east	5/5/09	ml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search history attached.	5/5/09	ml

	/M. Lee/ Primary Examiner.Art Unit 2622
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